The purpose of the BEA Customer Satisfaction Survey will be to obtain feedback from customers on the quality of BEA products and services. The results of the information collected will serve to assist BEA in improving the quality of its data products and its methods of dissemination.

II. Method of Collection

The survey and a cover letter with instructions on how to complete the survey will be mailed to about 5,000 potential respondents, BEA will request that responses be returned 30 days after the mailing. It will also reside on BEA's Web site for 2,000 potential respondents. The survey will be designed so that all responses are anonymous and therefore eliminates the necessity for record keeping of respondents.

III. Data

OMB Number: 0691–0001.

Type of Review: Reinstatement, without change of a previously approved collection.

Affected Public: Individuals from profit and non-profit organizations and individuals from other Federal, State, and local government agencies.

Estimated Number of Respondents: 500.

Estimated Response Time: 15 minutes.

Estimated Total Annual Burden Hours: 125.

Estimated Total Annual Cost: The only cost to the respondents is that of their time.

Legal Authority: Executive Order 12862, section 1(b), of September 11, 1993.

IV. Request for Comments

Comments are invited on: (a) Whether the proposed collection of information is necessary for the proper performance of the functions of the agency, including whether the information shall have practical utility; (b) the accuracy of the agency's estimate of the burden (including hours and cost) of the proposed collection of information; (c) ways to enhance the quality, utility, and clarity of the information to be collected; and (d) ways to minimize the burden of the collection of information on respondents, including through the use of automated collection techniques or other forms of information technology.

Comments submitted in response to this notice will be summarized and/or included in the request for OMB approval of this information collection; they also will be come a matter of public record.

Dated: December 9, 2003.

Madeleine Clayton,

Management Analyst, Office of the Chief Information Officer.

[FR Doc. 03–30845 Filed 12–12–03; 8:45 am]

BILLING CODE 3510–06–P

DEPARTMENT OF COMMERCE

International Trade Administration

Applications for Duty-Free Entry of Scientific Instruments

Pursuant to section 6(c) of the Educational, Scientific and Cultural Materials Importation Act of 1966 (Pub. L. 89–651; 80 Stat. 897; 15 CFR part 301), we invite comments on the question of whether instruments of equivalent scientific value, for the purposes for which the instruments shown below are intended to be used, are being manufactured in the United States.

Comments must comply with 15 CFR 301.5(a)(3) and (4) of the regulations and be filed within 20 days with the Statutory Import Programs Staff, U.S. Department of Commerce, Washington, DC 20230. Applications may be examined between 8:30 a.m. and 5 p.m. in Suite 4100W, U.S. Department of Commerce, Franklin Court Building, 1099 14th Street, NW., Washington, DC.

Docket Number: 03–051. *Applicant:* National Renewable Energy Laboratory, 1617 Cole Boulevard, Golden, CO 80401. *Instrument:* Electron Microscope, Model Tecnai G^2 20 TWIN. *Manufacturer:* FEI Company, the Netherlands. *Intended Use:* The instrument is intended to be used to study the structure and physical chemistry of biomass samples. The goal of these investigations is to better understand the structural and chemical properties and relate them to the susceptibility of biomass to enzyme digestion, and to characterize a variety of nano-structured materials such as quantum dot protein conjugates and polymeric supports for syngas conversion. *Application accepted by Commissioner of Customs:* November 13, 2003.

Docket Number: 03–052. *Applicant:* National Institute of Standards and Technology, 100 Bureau Drive, Gaithersburg, MD 20899. *Instrument:* Dual Beam Scanning Electron and Focused Ion Beam Microscope System, Model Nova 600 NanoLab. *Manufacturer:* FEI Company, the Netherlands. *Intended Use:* The instrument is intended to be used to study solid state materials and devices researched, used and produced by the microelectronics industry and emerging nanotechnology. The research objectives are to accurately measure small-size structures and to develop research and calibration methods. *Application accepted by Commissioner of Customs:* November 20, 2003.

Gerald A. Zerdy,

Program Manager, Statutory Import Programs Staff.

[FR Doc. 03–30900 Filed 12–12–03; 8:45 am]

BILLING CODE 3510–DS–P

DEPARTMENT OF COMMERCE

International Trade Administration

Whitehead Institute for Biomedical Research, et al.; Notice of Consolidated Decision on Applications for Duty-Free Entry of Electron Microscopes

This is a decision consolidated pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89–651, 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 a.m. and 5 p.m. in Suite 4100W, Franklin Court Building, U.S. Department of Commerce, 1099 14th Street, NW., Washington, DC.

Docket Number: 03–048. *Applicant:* Whitehead Institute for Biomedical Research, Cambridge, MA 02142. *Instrument:* Electron Microscope, Model JEM–2200FS. *Manufacturer:* JEOL Ltd., Japan. *Intended Use:* See notice at 68 FR 61189, October 27, 2003. *Order Date:* May 17, 1999.

Docket Number: 03–049. *Applicant:* National Institutes of Health, Bethesda, MD 20892–8008. *Instrument:* Electron Microscope, Model Tecnai G^2 Polara. *Manufacturer:* FEI Company, The Netherlands. *Intended Use:* See notice at 68 FR 61189, October 27, 2003. *Order Date:* June 18, 2003.

Comments: None received. *Decision:* Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as these instruments are intended to be used, was being manufactured in the United States at the time the instruments were ordered. *Reasons:* Each foreign instrument is a conventional transmission electron microscope (CTEM) and is intended for research or scientific educational uses requiring a CTEM. We know of no CTEM, or any other instrument suited to these purposes, which was being manufactured in the United States either at the time of order of each instrument OR at the time of receipt of